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8	BRS	L8	0	7 and ((fail or defect\$5) with (shape or bound\$5 or contour) same (ratio or rate))	USPAT	2004/05/13 22:06
9	BRS	L9	47	(fail or defect\$5) adj bit with (compress\$3 or encod\$3 or cod\$3)	EPO; JPO; DERWEN T; IBM_TD B	2004/05/13 22:06
10	BRS	L10	13	9 and ((fail or defect\$5) with (area or map))	EPO; JPO; DERWEN T; IBM_TD B	2004/05/13 22:07
11	BRS	L11	1	10 and ((fail or defect\$5) with (shape or bound\$5 or contour))	US-PGP UB; EPO; JPO; DERWEN T; IBM_TD B	2004/05/13 22:08

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#### 16 A method for storing fail bit maps in burn-in memory testers

*Isono, A.; Iguchi, Y.;*

Electronic Design, Test and Applications, 2002. Proceedings. The First IEEE International Workshop on , 29-31 Jan. 2002

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